nexperia

Reliability Monitoring Results

Quarters: Q1/2021 to Q4/2021

Based on structural similarity

| Suppli Nexperia | | User Part Number 74AUP3G07GT | | | | |
|--------------------|--|--|-----------------------------|-----------|------------|--------------|
| | escription: Triple buffer; o | | | | | |
| Proc Pac | iction Family: AUP cess family: C075 kage family: XSON | | | | | # |
| JESD4 | | Test Conditions | Duration | # Lots | # Quantity | Rejects |
| # 1 | TEST Pre- and Post-Stress Electrical Test | Tamb = 25 °C | N/A | see below | all parts | see below |
| # 2 | PC Preconditioning | JESD22-A113 MSL 1 | N/A | 1007 | 27163 | 0 |
| # 5a | HTOL EFR High Temperature Operating Life Extrinsic | JESD22-A108 Tj = 150°C V _{CCMAX} \leq V \leq 1.2*V _{CCMAX} | 48 hours or 168 hours | 219 | 38230 | 0 |
| # 5b | HTOL IFR High Temperature Operating Life Intrinsic | JESD22-A108 Tj = 150°C V _{CCMAX} \leq V \leq 1.2*V _{CCMAX} | ≥500 hours | 84 | 6277 | 0 |
| # 7 | TC Temperature Cycling | JESD22-A104 -65 °C to 150°C | ≥500 cycles | 548 | 15036 | 0 |
| # 9 | uHAST / HAST unbiased or biased High Accelerated Stress Test | JESD22-A101 Tamb = 130 °C, RH = 85%, V = V _{CCMAX} | 96 hours | 520 | 12127 | 0 |

Calculation of PPM, FIT and MTTF

Test considered for PPM calculation: High Temperature Operating LifeTest Extrinsic (HTOL EFR, Test # 5a above) Test considered for FIT and MTTF calculations: High Temperature Operating LifeTest Intrinsic(HTOL IFR, Test # 5b above)

Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

| Product Family | Package Family | Quantity | Rejects | Extrinsic Failure Rate (PPM) | Intrinsic Failure Rate (FIT) | MTTF (hrs) |
|-------------------|-------------------|----------|---------|---------------------------------|---------------------------------|------------|
| AUP | XSON | 6277 | 0 | 24 | 0.7 | 1.5 E+09 |

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